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Application/Control No.	Applicant(s)/Patent under Reexamination	
10/750,824	TANAKA ET AL.	
Examiner	Art Unit	
Kim T. Huynh	2112	

SEARCHED				
Class	Subclass	Date	Examiner	
710	240-244	3/13/2006	кн	
710	107, 113	3/13/2006	КН	
710	305	3/13/2006	КН	

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NO (INCLUDING SEARCH	TES I STRATEGY	)
	DATE	EXMR
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